SHARP

Data Sheet

LRS1327/LRS1344
Stacked Chip
8M Flash Memory and 1M SRAM

FEATURES

- Flash Memory and SRAM
- Stacked Die Chip Scale Package
  - LRS1327 bottom boot block
  - LRS1344 top boot block
- 64-ball 8 mm × 8 mm CSP plastic package
- Power supply: 2.7 V to 3.6 V
- Operating temperature: -40°C to +85°C
- Flash Memory
  - Access time (MAX.): 90 ns
  - Operating current (MAX.):
    The current for F-V_{CC} pin
    - Read: 25 mA (t_{CYCLE} = 200 ns)
    - Word write: 17 mA
    - Block erase: 17 mA
  - Deep power down current (the current for F-V_{CC} pin):
    - 20 µA (MAX. F-$\overline{CE}$ ≥ F-V_{CC} - 0.2 V, F-$\overline{RP}$ ≤ 0.2 V, F-V_{PP} ≤ 0.2 V)
  - Optimized array blocking architecture
    - Two 4K-word boot blocks
    - Six 4K-word parameter blocks
    - Fifteen 32K-word main blocks
    - Bottom boot location
  - Extended cycling capability
    - 100,000 block erase cycles
  - Enhanced automated suspend options
    - Word write suspend to read
    - Block erase suspend to word write
    - Block erase suspend to read
- SRAM
  - Access time (MAX.): 85 ns
  - Operating current: 45 mA (MAX.)
  - Standby current: 45 µA (MAX.)
  - Data retention current: 1 µA (MAX.)

DESCRIPTION

The LRS1327/LRS1344 is a combination memory organized as 524,288 × 16-bit flash memory and 65,536 × 16-bit static RAM in one package.

PIN CONFIGURATION

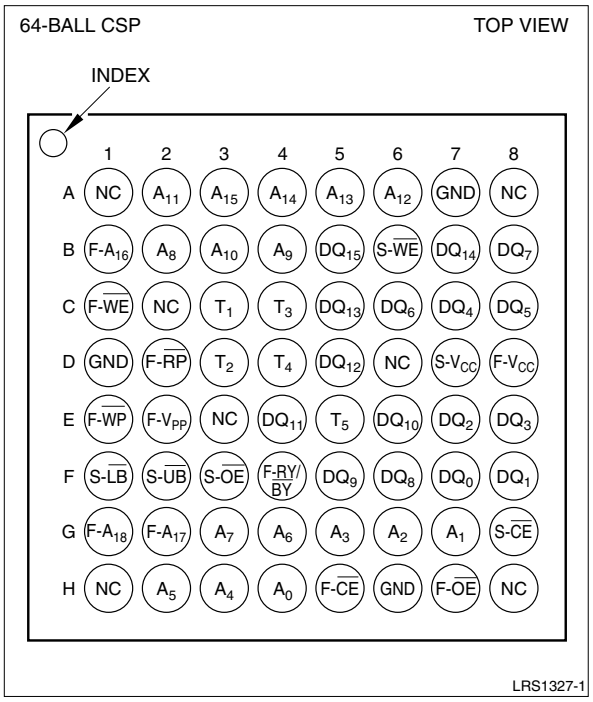


Figure 1. LRS1327/LRS1344 Pin Configuration

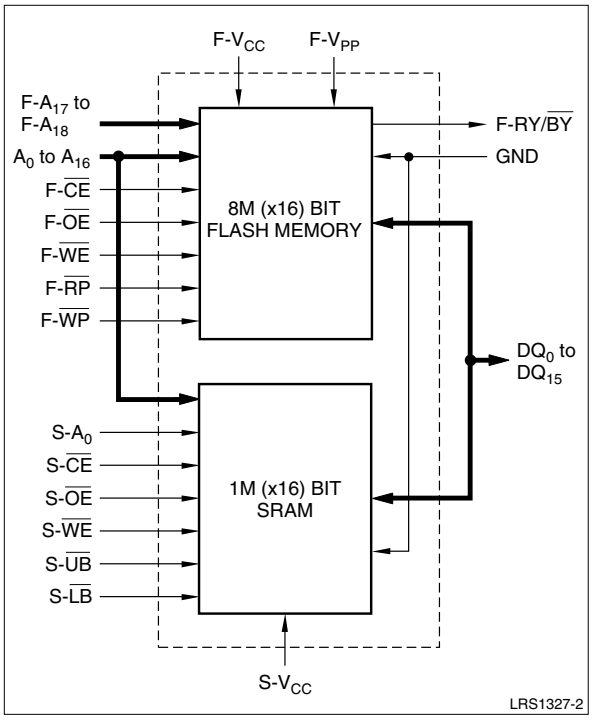


Figure 2. LRS1327/LRS1344 Block Diagram

Table 1. Pin Descriptions

PIN	DESCRIPTION	TYPE
A_0 to A_{15}	Address Inputs (Common)	Input
F-A_{16} to F-A_{18}	Address Inputs (Flash)	Input
F-$\overline{CE}$	Chip Enable Input (Flash)	Input
S-$\overline{CE}$	Chip Enable Input (SRAM)	Input
F-$\overline{WE}$	Write Enable Input (Flash)	Input
S-$\overline{WE}$	Write Enable Input (SRAM)	Input
F-$\overline{OE}$	Output Enable Input (Flash)	Input
S-$\overline{OE}$	Output Enable Input (SRAM)	Input
S-$\overline{LB}$	SRAM Byte Enable Input (DQ_0 to DQ_7)	Input
S-$\overline{UB}$	SRAM Byte Enable Input (DQ_8 to DQ_{15})	Input
F-$\overline{RP}$	Deep Power Down (Flash) Block Erase and Word Write: V_{IH} or V_{HH} Read: V_{IH} or V_{HH} Deep Power Down: V_{IL}	Input
F-$\overline{WP}$	Write Protect (Flash) Two Boot Blocks Locked: V_{IL} (with F-$\overline{RP}$ = V_{HH} Erase of Write can operate to all blocks)	Input
F-RY/$\overline{BY}$	Ready/Busy (Flash) During an Erase or Write operation: V_{OL} Block Erase and Word Byte Write Suspend: HIGH-Z Deep Power Down: V_{OH}	Open Drain Output
DQ_0 to DQ_{15}	Data Input/Outputs (Common)	Input/Output
F-V_{CC}	Power Supply (Flash)	Power
S-V_{CC}	Power Supply (SRAM)	Power
F-V_{PP}	Write, Erase Power Supply (Flash) Block Erase and Word Write: F-V_{PP} = V_{PPLK} All Blocks Locked: F-V_{PP} < V_{PPLK}	
GND	Ground (Common)	Power
NC	No Connection	—
T_1 to T_5	Test Pins (Should be Open)	—

Table 2. Truth Table[1]

FLASH	SRAM	F-$\overline{CE}$	F-$\overline{RP}$	F-$\overline{OE}$	F-$\overline{WE}$	S-$\overline{CE}$	S-$\overline{OE}$	S-$\overline{WE}$	S-$\overline{LB}$	S-$\overline{UB}$	DQ_0 - DQ_{15}	NOTES
Read	Standby	L	H	L	H	H	X	X	X	X	D_{OUT}	2, 3
Output Disable	Standby	L	H	H	H	H	X	X	X	X	HIGH-Z	3
Write	Standby	L	H	H	L	H	X	X	X	X	D_{IN}	2, 3, 4, 5
Standby	Read	H	H	X	X	L	L	H	See Note 6			
	Output Disable	H	H	X	X	L	H	H	X	X	HIGH-Z	
		H	H	X	X	L	X	X	H	H	HIGH-Z	
	Write	H	H	X	X	L	L	L	See Note 6			
Deep Power Down	Read	X	L	X	X	L	L	H	See Note 6			
	Output Disable	X	L	X	X	L	H	H	X	X	HIGH-Z	
		X	L	X	X	L	X	X	H	H	HIGH-Z	
	Write	X	L	X	X	L	L	L	See Note 6			
Standby	Standby	H	H	X	X	H	X	X	X	X	HIGH-Z	3
Deep Power Down	Standby	X	L	X	X	H	X	X	X	X	HIGH-Z	3

NOTES:
1. L = V_{IL}, H = V_{IH}, X = H or L. Refer to DC Characteristics.
2. Refer to the 'Flash Memory Command Definition' section for valid D_{IN} during a write operation.
3. F-$\overline{WP}$ set to V_{IL} or V_{IH}.
4. Command writes involving block erase or word write are reliably executed when F-V_{PP} = V_{PPH} and F-V_{CC} = 2.7 V to 3.6 V. Block erase or word write with V_{IH} < F-$\overline{RP}$ < V_{HH} produce spurious results and should not be attempted.
5. Never hold F-$\overline{OE}$ LOW and F-$\overline{WE}$ LOW at the same timing.
6. S-$\overline{LB}$, S-$\overline{UB}$ control mode. See Table 2a.

Table 2a.

MODE (SRAM)	PINS			
	S-$\overline{LB}$	S-$\overline{UB}$	DQ_0 - DQ_7	DQ_8 - DQ_{15}
Read/Write	L	L	D_{OUT}/D_{IN}	D_{OUT}/D_{IN}
	L	H	D_{OUT}/D_{IN}	HIGH-Z
	H	L	HIGH-Z	D_{OUT}/D_{IN}

Table 3. Command Definition for Flash Memory[1]

COMMAND	BUS CYCLES REQUIRED	FIRST BUS CYCLE			SECOND BUS CYCLE			NOTES
		OPERATION[2]	ADDRESS[3]	DATA[3]	OPERATION[2]	ADDRESS[3]	DATA[3]	
Read Array/Reset	1	Write	XA	FFH				
Read Identifier Codes	≥ 2	Write	XA	90H	Read	IA	ID	4
Read Status Register	2	Write	XA	70H	Read	XA	SRD	
Clear Status Register	1	Write	XA	50H				
Block Erase	2	Write	BA	20H	Write	BA	D0H	5
Word Write	2	Write	WA	40H or 10H	Write	WA	WD	5
Block Erase and Word Write Suspend	1	Write	XA	B0H				5
Block Erase and Word Write Resume	1	Write	XA	D0H				5

NOTES:
1. Commands other than those shown in table are reserved by SHARP for future device implementations and should not be used.
2. BUS operations are defined in Table 2.
3. XA = Any valid address within the device; IA = Identifier code address; BA = Address within the block being erased; WA = Address of memory location to be written; SRD = Data read from status register; WD = Data to be written at location WA. Data is latched on the rising edge of F-$\overline{WE}$ or F-$\overline{CE}$ (whichever goes HIGH first); ID = Data read from identifier codes.
4. See Table 4 for Identifier Codes.
5. See Table 5 for Write Protection Alternatives.

Table 4. Identifier Codes

CODES	ADDRESS (A_0 - A_8)	LRS1327 DATA (DQ_0 - DQ_7)	LRS1344 DATA (DQ_0 - DQ_7)
Manufacture Code	00000H	B0H	B0H
Device Code	00001H	4BH	60H

Table 5. Write Protection Alternatives

OPERATION	F-V_{PP}	F-$\overline{RP}$	F-$\overline{WP}$	EFFECT
Block Erase or Word Write	V_{IL}	X	X	All blocks locked
	> V_{PPLK}	V_{IL}	X	All blocks locked
		V_{HH}	X	All blocks unlocked
		V_{IH}	V_{IL}	Two boot blocks locked
		V_{IH}	V_{IH}	All blocks unlocked

Table 6. Status Register Definition

WSMS	ESS	ES	WWS	VPPS	WWSS	DPS	R
7	6	5	4	3	2	1	0

SR.7 = Write State Machine Status (WSMS)
- 1 = Ready
- 0 = Busy

SR.6 = Erase Suspend Status (ESS)
- 1 = Block Erase Suspended
- 0 = Block Erase in Progress/Completed

SR.5 = Erase Status (ES)
- 1 = Error in Block Erasure
- 0 = Successful Block Erase

SR.4 = Word Write Status (WWS)
- 1 = Error in Word Write
- 0 = Successful Word Write

SR.3 = V_{PP} Status (VPPS)
- 1 = F-V_{PP} LOW Detect, Operation Abort
- 0 = F-V_{PP} Okay

SR.2 = Word Write Suspend Status (WWSS)
- 1 = Word Write Suspended
- 0 = Word Write in Progress/Completed

SR.1 = Device Protect Status (DPS)
- 1 = F-$\overline{WP}$ and/or F-$\overline{RP}$ Lock Detected, Operation Abort
- 0 = Unlock

SR.0 = Reserved for future enhancements (R)

NOTES:
1. Check RY/$\overline{BY}$ or SR.7 to determine block erase or word write completion. SR.6 - SR.0 are invalid while SR.7 = 0.
2. If both SR.5 and SR.4 are '1's after a block erase attempt, an improper command sequence was entered.
3. SR.3 does not provide a continuous indication of F-V_{PP} level. The WSM interrogates and indicates the F-V_{PP} level only after Block Erase or Word Write command sequences. SR.3 is not guaranteed to report accurate feedback only when F-$V_{PP} \neq V_{PPH1}$, V_{PPH2}.
4. The WSM interrogates the F-$\overline{WP}$ and F-$\overline{RP}$ only after Block Erase or Word Write command sequences. It informs the system, depending on the attempted operation, if the F-$\overline{WP}$ is not V_{IH} or F-$\overline{RP}$ is not V_{HH}.
5. SR.0 is reserved for future use and should be masked out when polling the status register.

MEMORY MAP

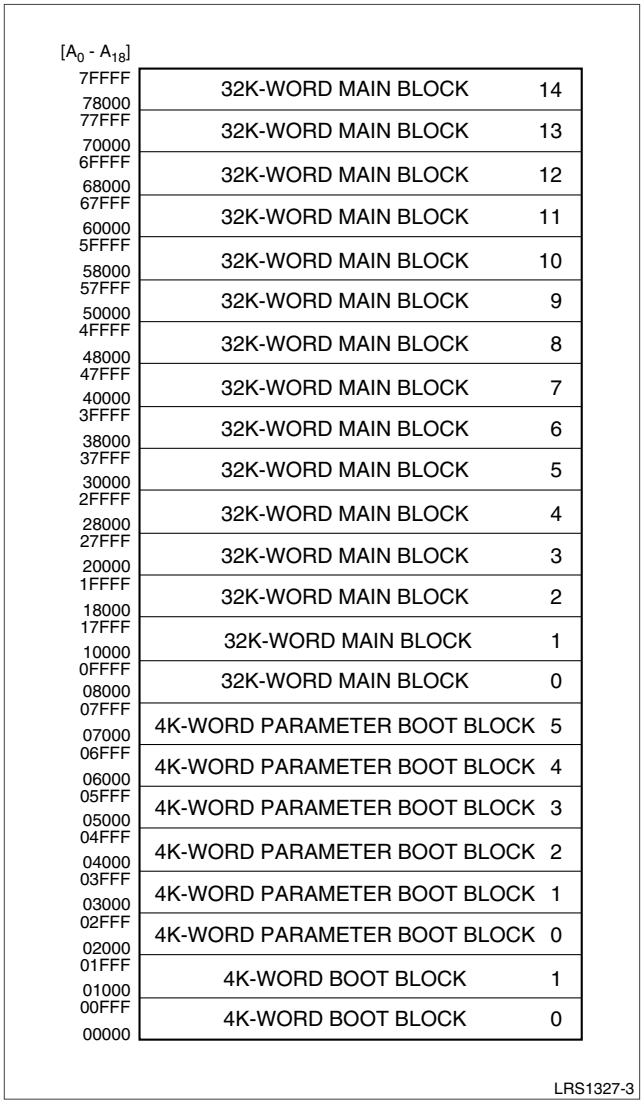


Figure 3. LRS1327 Bottom Boot Memory Map

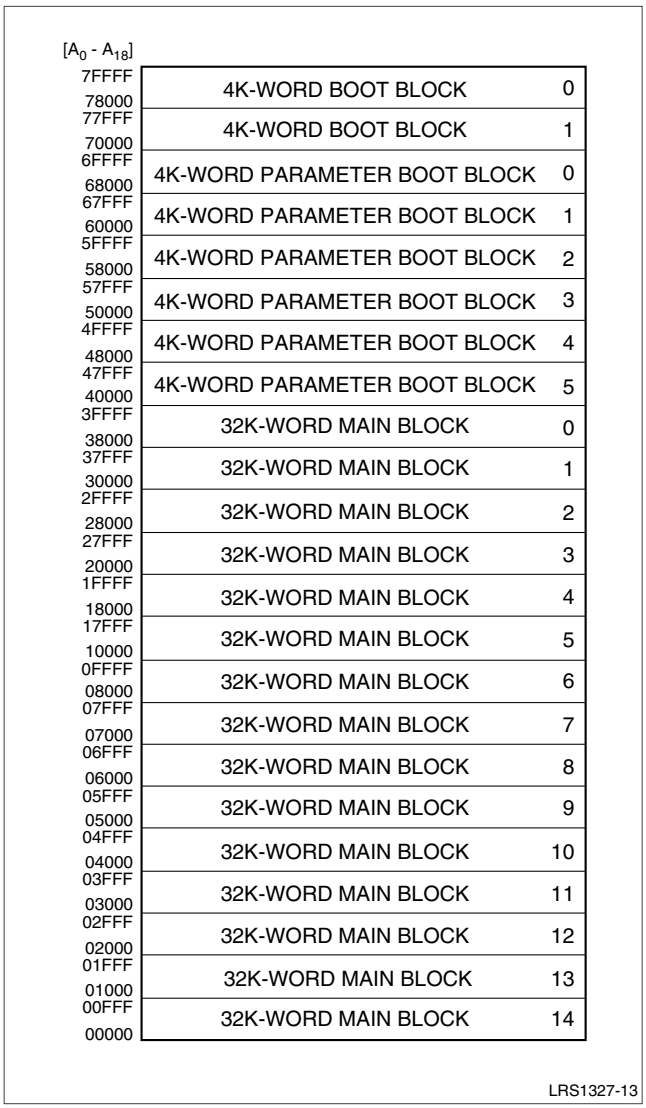


Figure 4. LRS1344 Top Boot Memory Map

ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	RATINGS	UNIT	NOTES
Supply voltage	V_{CC}	-0.3 to +4.6	V	1, 2
Input voltage	V_{IN}	-0.3 to V_{CC} +0.3	V	1, 2, 3, 4
Operating temperature	T_{OPR}	-40 to +85	°C	
Storage temperature	T_{STG}	-65 to +125	°C	
F-V_{PP} voltage	F-V_{PP}	-0.2 to +14.0	V	1, 4, 5
F-$\overline{RP}$ voltage	F-$\overline{RP}$	-0.5 to +14.0	V	1, 4, 5

NOTES:
1. The maximum applicable voltage on any pins with respect to GND.
2. Except F-V_{PP}.
3. Except F-$\overline{RP}$.
4. -2.0 V undershoot is allowed when the pulse width is less than 20 ns.
5. +14.0 V overshoot is allowed when the pulse width is less than 20 ns.

RECOMMENDED DC OPERATING CONDITIONS

T_A = -40°C to +85°C

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	NOTES
Supply voltage	V_{CC}	2.7	3.0	3.6	V	
Input voltage	V_{IH}	2.0		V_{CC} + 0.3	V	1
	V_{IL}	-0.3		0.8	V	2
	V_{HH}	11.4		12.6	V	3

NOTES:
1. V_{CC} is the lower one of S-V_{CC} and F-V_{CC}.
2. -2.0 V undershoot is allowed when the pulse width is less than 20 ns.
3. This voltage is applicable to F-$\overline{RP}$ pin only.

PIN CAPACITANCE

T_A = 25°C, f = 1 MHz

PARAMETER	SYMBOL	CONDITION	MIN.	TYP.	MAX.	UNIT
Input capacitance*	C_{IN}	V_{IN} = 0 V			20	pF
I/O capacitance*	$C_{I/O}$	$V_{I/O}$ = 0 V			22	pF

NOTE: *Sampled by not 100% tested.

DC CHARACTERISTICS

T_A = -40°C to + 85°C, V_{CC} = 2.7 V to 3.6 V

PARAMETER		SYMBOL	CONDITION	MIN.	TYP.[1]	MAX.	UNIT	NOTES
Input leakage current		I_{LI}	$V_{IN} = V_{CC}$ or GND	-1.5		+1.5	µA	
Output leakage current		I_{LO}	$V_{OUT} = V_{CC}$ or GND	-1.5		+1.5	µA	
F-V_{CC}	Standby Current	I_{CCS}	F-$\overline{CE}$ = F-$\overline{RP}$ = F-V_{CC} ± 0.2 V F-$\overline{WP}$ = F-V_{CC} ± 0.2 V or F-GND ± 0.2 V		25	50	µA	2
			F-$\overline{CE}$ = F-$\overline{RP}$ = V_{IH}, F-$\overline{WP}$ = V_{IH} or V_{IL}		0.2	2	mA	2
	Deep PowerDown Current	I_{CCD}	F-$\overline{RP}$ = F-GND ± 0.2 V, I_{OUT} (F-RY/$\overline{BY}$) = 0 mA		5	20	µA	
	Read Current	I_{CCR}	CMOS input, F-$\overline{CE}$ = F-GND, f = 5 MHz, I_{OUT} = 0 mA		15	25	mA	3, 4
			TTL input, F-$\overline{CE}$ = F-GND, f = 5 MHz, I_{OUT} = 0 mA			30	mA	3, 4
	Word Write Current	I_{CCW}	F-V_{PP} = V_{PPH}		5	17	mA	
	Block Erase Current	I_{CCE}	F-V_{PP} = V_{PPH}		4	17	mA	
	Word Write Block Erase Suspend Current	I_{CCWS} I_{CCES}	F-$\overline{CE}$ = V_{IH}		1	6	mA	
F-V_{PP}	Standby or Read Current	I_{PPS} I_{PPR}	F-V_{PP} = F-V_{CC}		±2	±15	µA	
			F-V_{PP} > F-V_{CC}		10	200	µA	
	Deep Power Down Current	I_{PPD}	F-$\overline{RP}$ = F-GND ± 0.2 V		0.1	5	µA	
	Word Write Current	I_{PPW}	F-V_{PP} = V_{PPH}		12	40	mA	
	Block Erase Current	I_{PPE}	F-V_{PP} = V_{PPH}		8	25	mA	
	Word Write or Block Erase Suspend Current	I_{PPWS} I_{PPES}	F-V_{PP} = V_{PPH}		10	200	µA	
S-V_{CC}	Standby Current	I_{SB}	S-$\overline{CE}$ ≥ S-V_{CC} - 0.2 V		25	45	µA	
		I_{SB1}	S-$\overline{CE}$ = V_{IH}			3	mA	
	Operation Current	I_{CC1}	S-$\overline{CE}$ = V_{IL}, V_{IN} = V_{IL} or V_{IH}, t_{CYCLE} = MIN., $I_{I/O}$ = 0 mA		0.5	45	mA	
		I_{CC2}	S-$\overline{CE}$ ≤ 0.2 V, V_{IN} = S-V_{CC} - 0.2 V, or 0.2 V, t_{CYCLE} = 1 µs, $I_{I/O}$ = 0 mA			5	mA	
Input LOW Voltage		V_{IL}		-0.3		0.8	V	
Input HIGH Voltage		V_{IH}		2.0		V_{CC} + 0.3	V	
Output LOW Voltage		V_{OL}	I_{OL} = 2.0 mA			0.4	V	2
Output HIGH Voltage (TTL)		V_{OH1}	I_{OH} = -1.0 mA	2.4			V	2
Output HIGH Voltage (CMOS)		V_{OH2}	I_{OH} = -2.0 mA	0.85 V_{CC}			V	2
			I_{OH} = 100 µA	V_{CC} - 0.4			V	2
F-V_{PP} Lockout during Normal Operations		V_{PPLK}				1.5	V	5
F-V_{PP} Word Write or Block Erase Operations		V_{PPH}		2.7		3.6	V	
F-V_{CC} Lockout Voltage		V_{LKO}		2.0			V	
F-$\overline{RP}$ Unlock Voltage		V_{HH}	Unavailable F-$\overline{WP}$	11.4		12.6	V	6

NOTES:

1. Reference values at V_{CC} = 3.0 V and T_A = +25°C.
2. Includes F-RY/$\overline{BY}$.
3. Automatic Power Savings (APS) for Flash Memory reduces typical I_{CCR} to 3 mA at 2.7 V V_{CC} in static operation.
4. CMOS inputs are either V_{CC} ± 0.2 V or GND ± 0.2 V. TTL inputs are either V_{IL} or V_{IH}.
5. Block erases and word writes are inhibited when F-V_{PP} ≤ V_{PPLK} and not guaranteed in the range between V_{PPLK} (MAX.) and V_{PPH} (MIN.), and above V_{PPH} (MAX.).
6. F-$\overline{RP}$ connection to a V_{HH} supply is allowed for a maximum cumulative period of 80 hours.

FLASH MEMORY AC CHARACTERISTICS

AC Test Conditions

PARAMETER	CONDITION
Input pulse level	0 V to 2.7 V
Input rise and fall time	5 ns
Input and Output timing reference level	1.35 V
Output load	1TTL + C_L (30 pF)

Read Cycle

T_A = -40°C to +85°C, V_{CC} = 2.7 V to 3.6 V

PARAMETER	SYMBOL	MIN.	MAX.	UNIT
Read Cycle Time	t_{AVAV}	90		ns
Address to Output Delay	t_{AVQV}		90	ns
F-$\overline{CE}$ to Output Delay*	t_{ELQV}		90	ns
F-$\overline{RP}$ HIGH to Output Delay	t_{PHQV}		600	ns
F-$\overline{OE}$ to Output Delay*	t_{GLQV}		50	ns
F-$\overline{CE}$ to Output in LOW Z	t_{ELQX}	0		ns
F-$\overline{CE}$ HIGH to Output in HIGH-Z	t_{EHQZ}		55	ns
F-$\overline{OE}$ to Output in LOW Z	t_{GLQX}	0		ns
F-$\overline{OE}$ HIGH to Output in HIGH-Z	t_{GHQZ}		20	ns
Output Hold from Address, F-$\overline{CE}$ or F-$\overline{OE}$ change, whichever occurs first	t_{OH}	0		ns

NOTE: *F-$\overline{OE}$ may be delayed up to t_{ELQV} - t_{GLQV} after the falling edge of F-$\overline{OE}$ without impact on t_{ELQV}.

Write Cycle (F-$\overline{WE}$ Controlled)[1]

T_A = -40°C to +85°C, V_{CC} = 2.7 V to 3.6 V

PARAMETER	SYMBOL	MIN.	MAX.	UNIT	NOTES
Write Cycle Time	t_{AVAV}	90		ns	
F-$\overline{RP}$ HIGH Recovery to F-$\overline{WE}$ going to LOW	t_{PHWL}	1		µs	
F-$\overline{CE}$ Setup to F-$\overline{WE}$ going LOW	t_{ELWL}	10		ns	
F-$\overline{WE}$ Pulse Width	t_{WLWH}	50		ns	
F-$\overline{RP}$ V_{HH} Setup to F-$\overline{WE}$ going HIGH	t_{PHHWH}	100		ns	
F-$\overline{WP}$ V_{IH} Setup to F-$\overline{WE}$ going HIGH	t_{SHWH}	100		ns	
F-V_{PP} Setup to F-$\overline{WE}$ going HIGH	t_{VPWH}	100		ns	
Address Setup to F-$\overline{WE}$ going HIGH	t_{AVWH}	50		ns	2
Data Setup to F-$\overline{WE}$ going HIGH	t_{DVWH}	50		ns	2
Data Hold from F-$\overline{WE}$ HIGH	t_{WHDX}	0		ns	
Address Hold from F-$\overline{WE}$ HIGH	t_{WHAX}	0		ns	
F-$\overline{CE}$ Hold from F-$\overline{WE}$ HIGH	t_{WHEH}	10		ns	
F-$\overline{WE}$ Pulse Width HIGH	t_{WHWL}	30		ns	
F-$\overline{WE}$ HIGH to F-RY/$\overline{BY}$ going LOW	t_{WHRL}		100	ns	
Write Recovery before Read	t_{WHGL}	0		ns	
F-V_{PP} Hold from Valid SRD, F-RY/$\overline{BY}$ HIGH Z	t_{QVVL}	0		ns	
F-$\overline{RP}$ V_{HH} Hold from Valid SRD, F-RY/$\overline{BY}$ HIGH Z	t_{QVPH}	0		ns	
F-$\overline{WP}$ V_{IH} Hold from Valid SRD, F-RY/$\overline{BY}$ HIGH	t_{QVSL}	0		ns	

NOTES:

1. Read timing characteristics during block erase and word write operations are the same as during read-only operations. Refer to AC Characteristics for Read Cycle.
2. Refer to the 'Flash Memory Command Definition' section for valid A_{IN} and D_{IN} for block erase or word write.

Write Cycle (F-$\overline{CE}$ Controlled)[1]

T_A = -40°C to +85°C, V_{CC} = 2.7 V to 3.6 V

PARAMETER	SYMBOL	MIN.	MAX.	UNIT	NOTES
Write Cycle Time	t_{AVAV}	90		ns	
F-$\overline{RP}$ HIGH Recovery to F-$\overline{CE}$ going to LOW	t_{PHEL}	1		µs	
F-$\overline{WE}$ Setup to F-$\overline{CE}$ going LOW	t_{WLEL}	0		ns	
F-$\overline{CE}$ Pulse Width	t_{ELEH}	60		ns	
F-$\overline{rP}$ V_{HH} Setup to F-$\overline{CE}$ going HIGH	t_{PHHEH}	100		ns	
F-$\overline{WP}$ V_{IH} Setup to F-$\overline{CE}$ going HIGH	t_{SHEH}	100		ns	
F-V_{PP} Setup to F-$\overline{CE}$ going HIGH	t_{VPEH}	100		ns	
Address Setup to F-$\overline{CE}$ going HIGH	t_{AVEH}	50		ns	
Data Setup to F-$\overline{CE}$ going HIGH	t_{DVEH}	50		ns	2
Data Hold from F-$\overline{CE}$ HIGH	t_{EHDX}	0		ns	2
Address Hold from F-$\overline{CE}$ HIGH	t_{EHAX}	0		ns	
F-$\overline{WE}$ Hold from F-$\overline{CE}$ HIGH	t_{EHWH}	0		ns	
F-$\overline{CE}$ Pulse Width HIGH	t_{EHEL}	20		ns	
F-$\overline{CE}$ HIGH to F-RY/$\overline{BY}$ going LOW	t_{EHRL}		100	ns	
Write Recovery before Read	t_{EHGL}	0		ns	
F-V_{PP} Hold from Valid SRD, F-RY/$\overline{BY}$ HIGH Z	t_{QVVL}	0		ns	
F-$\overline{RP}$ V_{HH} Hold from Valid SRD, F-RY/$\overline{BY}$ HIGH	t_{QVPH}	0		ns	
F-$\overline{WP}$ V_{IH} Hold from Valid SRD, F-RY/$\overline{BY}$ HIGH	t_{QVSL}	0		ns	

NOTES:
1. Read timing characteristics during block erase and word write operations are the same as during read-only operations. Refer to AC Characteristics for Read Cycle.
2. Refer to the 'Flash Memory Command Definition' section for valid A_{IN} and D_{IN} for block erase or word write.

Block Erase and Word Write Performance

T_A = -40°C to +85°C, V_{CC} = 2.7 V to 3.6 V

SYMBOL	PARAMETER	V_{PP} = 2.7 V to 3.6 V			V_{PP} = 11.4 V to 12.6 V			UNIT	NOTES
		MIN.	TYP.[1]	MAX.	MIN.	TYP.[1]	MAX.		
t_{WHQV1} t_{EHQV1}	Word Write Time 32K-word Block		44.6			12.6		µs	2
	Word Write Time 4K-word Block		45.9			24.5		µs	2
	Block Write Time 32K-word Block		1.46			0.42		s	2, 3
	Block Write Time 4K-word Block		0.19			0.11		s	2, 3
t_{WHQV2} t_{EHQV2}	Block Erase Time 32K-word Block		1.14			0.51		s	2
	Block Erase Time 4K-word Block		0.38			0.31		s	2
t_{WHRZ1} t_{EHRZ1}	Word Write Suspend Latency Time to Read		7	8	8	6	7	µs	
t_{WHRZ2} t_{EHRZ2}	Erase Suspend Latency Time to Read		18	22	22	11	14	µs	

NOTES:
1. Reference values at T_A = +25°C and V_{CC} = 3.0 V, V_{PP} = 3.0 V or V_{CC} = 3.0 V, V_{PP} = 12.0 V. Subject to change based on device characterization.
2. Excludes system-level overhead.
3. All values are in word mode ($\overline{BYTE}$ = V_{IH}). At byte mode ($\overline{BYTE}$ = V_{IL}), those values are doubled.
4. Sampled but not 100% tested.

FLASH MEMORY AC CHARACTERISTICS TIMING DIAGRAMS

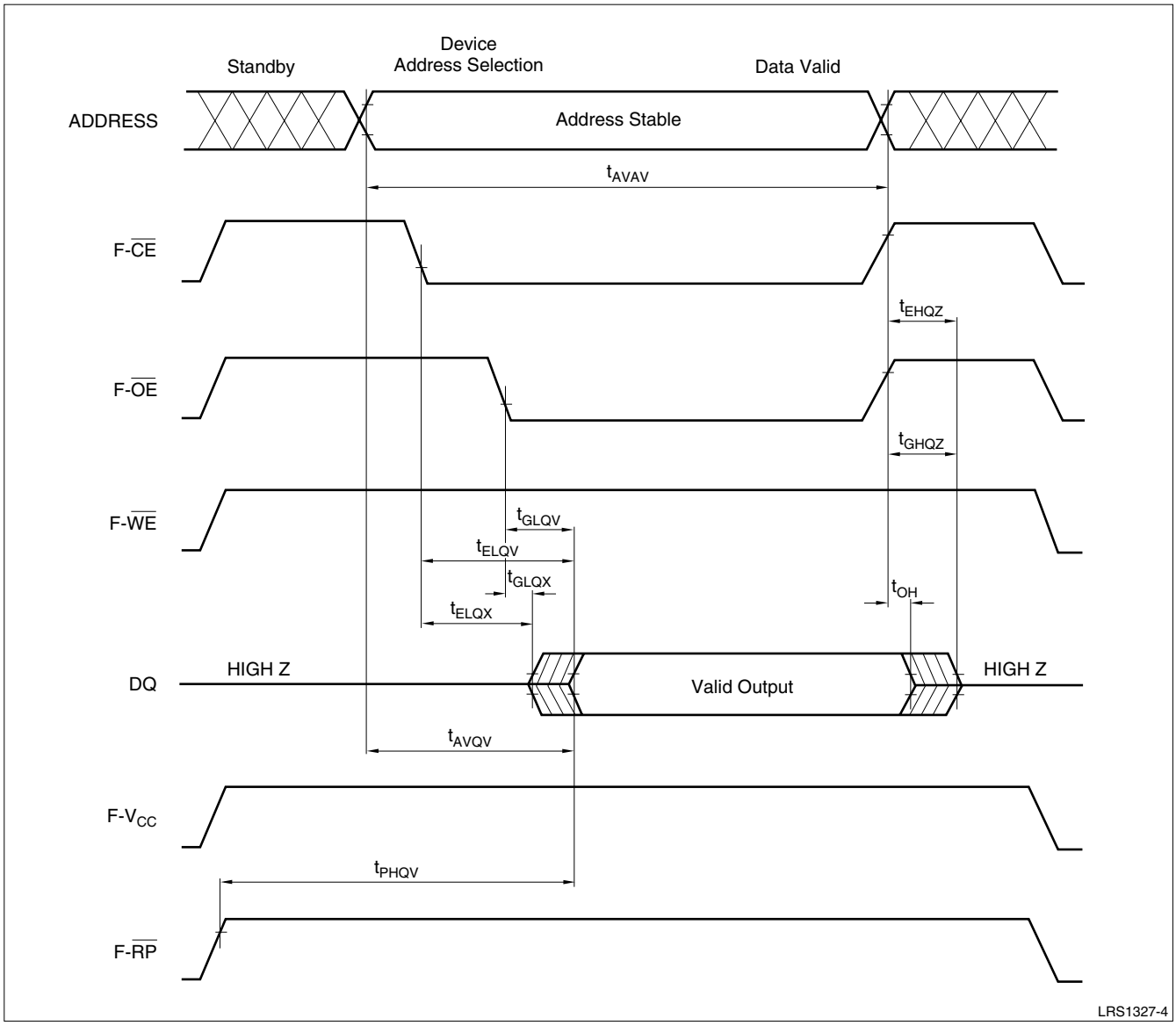
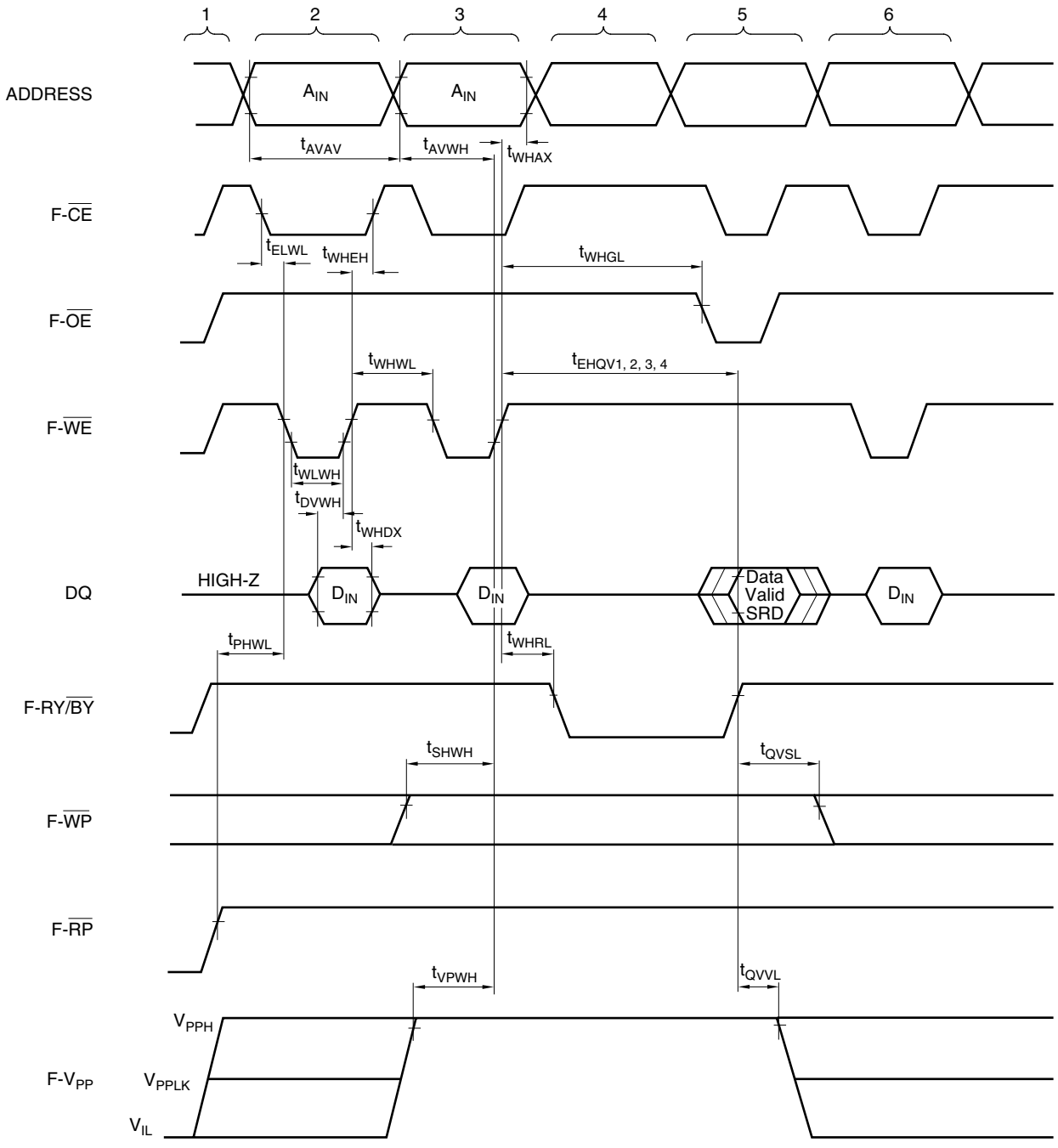


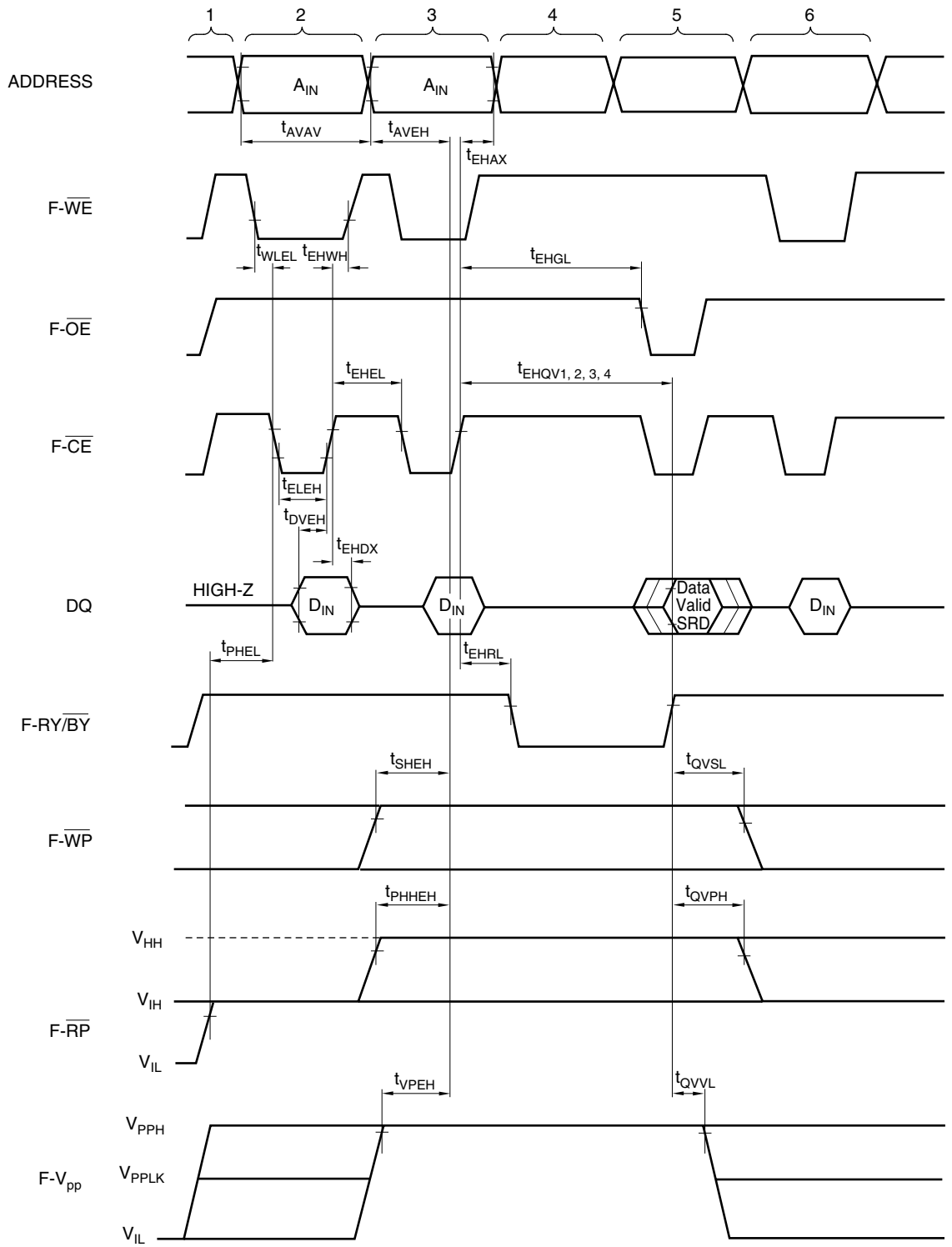
Figure 5. Read Cycle Timing Diagram



NOTES:
1. V_{CC} power-up and standby.
2. Write block erase or word write setup.
3. Write block erase confirm or valid address and data.
4. Automated erase or program delay.
5. Read status register data.
6. Write Read Array command.

LRS1327-5

Figure 6. Write Cycle Timing Diagram (F-$\overline{WE}$ Controlled)



NOTES:
1. V_{CC} power-up and standby.
2. Write block erase or word write setup.
3. Write block erase confirm or valid address and data.
4. Automated erase or program delay.
5. Read status register data.
6. Write Read Array command.

LRS1327-6

Figure 7. Write Cycle Timing Diagram (F-$\overline{CE}$ Controlled)

RESET OPERATIONS

T_A = -40°C to +85°C, V_{CC} = 2.7 V to 3.6 V

PARAMETER	SYMBOL	MIN.	MAX.	UNIT	NOTES
F-$\overline{RP}$ Pulse LOW Time (if F-$\overline{RP}$ is tied to V_{CC}, this specification is not applicable).	t_{PLPH}	100		ns	
F-$\overline{RP}$ LOW to Reset during Block Erase or Word Write	t_{PLRZ}		22	µs	1, 2
F-V_{CC} 2.7 V to F-$\overline{RP}$ HIGH	t_{VPH}	100		ns	3

NOTES:
1. If F-$\overline{RP}$ is asserted while a block erase or word write operations is not executing, the reset will complete with 100 ns.
2. A reset time t_{PHQV} is required from the later of F-RY/$\overline{BY}$ going HIGH Z of F-$\overline{RP}$ going HIGH until outputs are valid.
3. When the device power-up, holding F-$\overline{RP}$ LOW minimum 100 ns is required after V_{CC} has been in predefined range and also has been stable there.

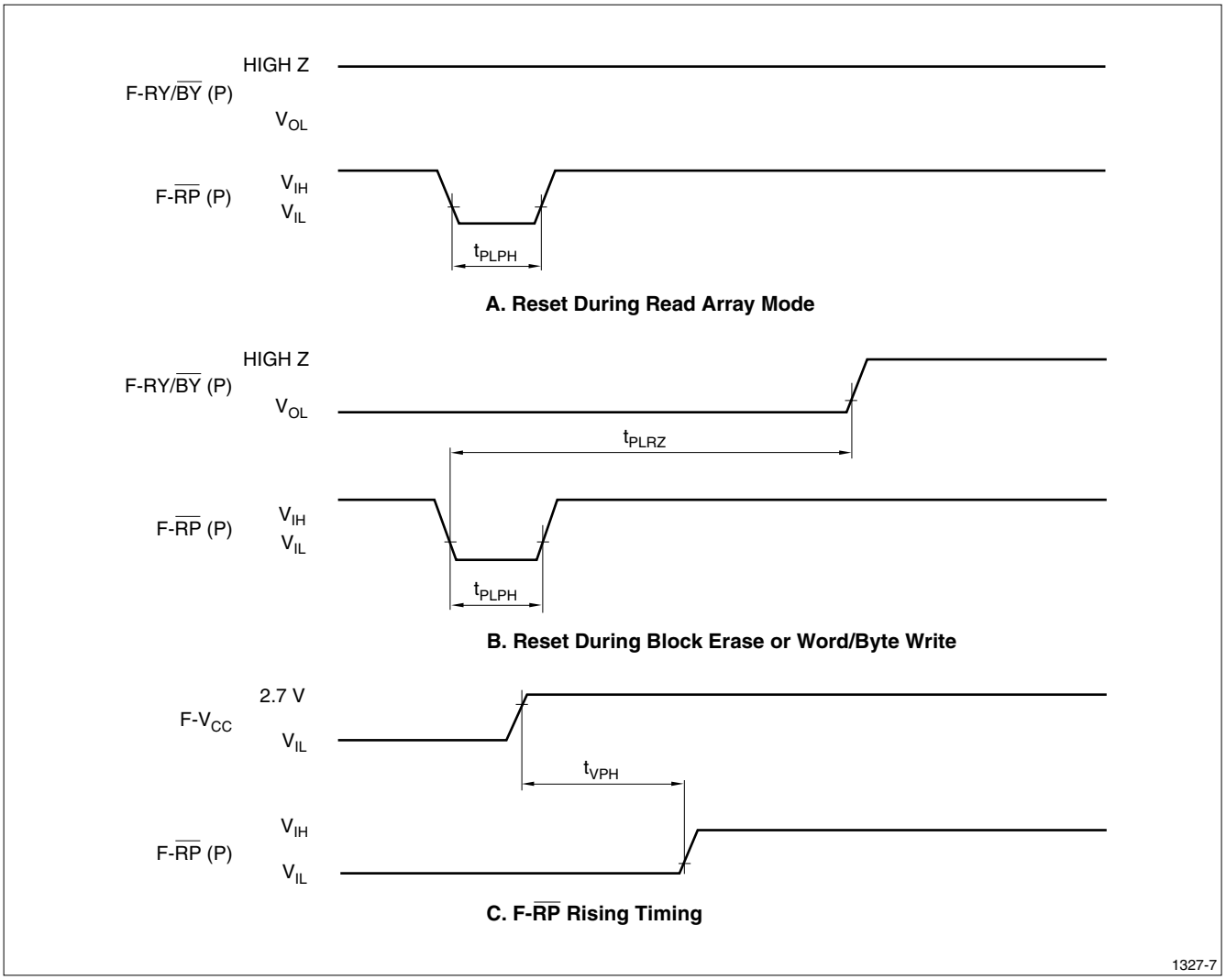


Figure 8. AC Waveform for Reset Operation

SRAM AC ELECTRICAL CHARACTERISTICS

AC Test Conditions

PARAMETER	CONDITION
Input pulse level	0.6 V to 2.4 V
Input rise and fall time	5 ns
Input and Output timing reference level	1.4 V
Output load*	1TTL + C_L (30 pF)

NOTE: *Including scope and jig capacitance.

Read Cycle

T_A = -40°C to +85°C, V_{CC} = 2.7 V to 3.6 V

PARAMETER	SYMBOL	MIN.	MAX.	UNIT
Read Cycle Time	t_{RC}	85		ns
Address Access Time	t_{AA}		85	ns
Chip Enable Access Time (S-$\overline{CE}$)	t_{ACE}		85	ns
Byte Enable Access Time	t_{BE}		85	ns
Output Enable to Output Valid	t_{OE}		45	ns
Output hold from address change	t_{OH}	10		ns
S-$\overline{CE}$ LOW to Output Active*	t_{LZ}	10		ns
S-$\overline{OE}$ LOW to Output Active*	t_{OLZ}	5		ns
S-$\overline{UB}$ or S-$\overline{LB}$ LOW to Output in HIGH Impedance*	t_{BLZ}	5		ns
S-$\overline{CE}$ HIGH to Output in HIGH Impedance*	t_{HZ}	0	40	ns
S-$\overline{OE}$ HIGH to Output in HIGH Impedance*	t_{OHZ}	0	35	ns
S-$\overline{UB}$ or S-$\overline{LB}$ HIGH to Output Active*	t_{BHZ}	0	35	ns

NOTE: *Active output to HIGH impedance and HIGH impedance to output active tests specified for a ±200 mV transition from steady state levels into the test load.

Write Cycle

T_A = -40°C to +85°C, V_{CC} = 2.7 V to 3.6 V

PARAMETER	SYMBOL	MIN.	MAX.	UNIT
Write Cycle Time	t_{WC}	85		ns
Chip Enable to End of Write	t_{CW}	75		ns
Address Valid to End of Write	t_{AW}	75		ns
Byte Enable Access Time	t_{BW}	75		ns
Address Setup Time	t_{AS}	0		ns
Write Pulse Width	t_{WP}	65		ns
Write Recovery Time	t_{WR}	0		ns
Input Data Setup Time	t_{DW}	35		ns
Input Data Hold Time	t_{DH}	0		ns
S-$\overline{WE}$ HIGH to Output Active*	t_{OW}	5		ns
S-$\overline{WE}$ LOW to Output in HIGH Impedance*	t_{WZ}	0	40	ns

NOTE: *Active output to HIGH impedance and HIGH impedance to output active tests specified for a ±200 mV transition from steady state levels into the test load.

SRAM AC CHARACTERISTICS TIMING DIAGRAMS

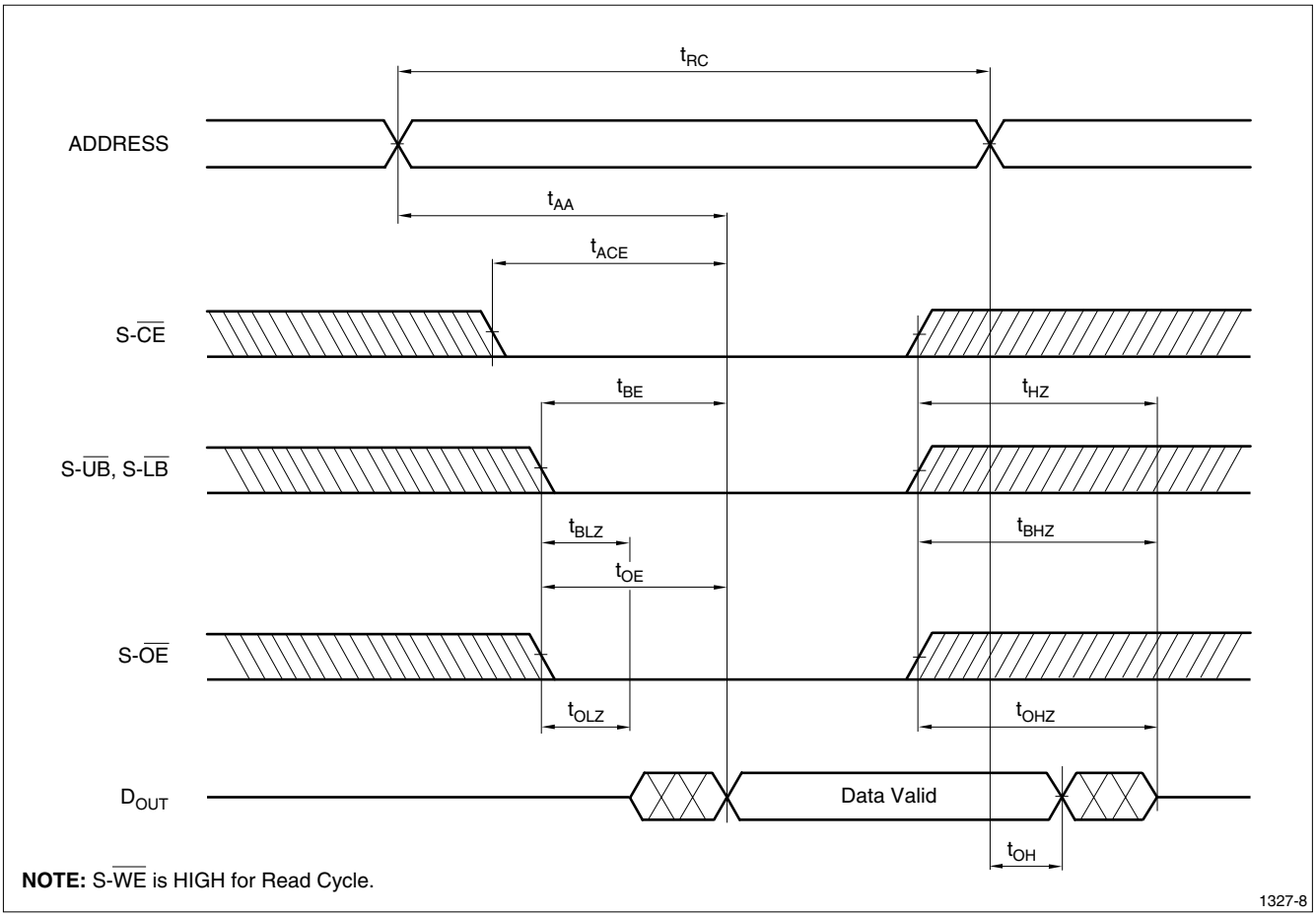
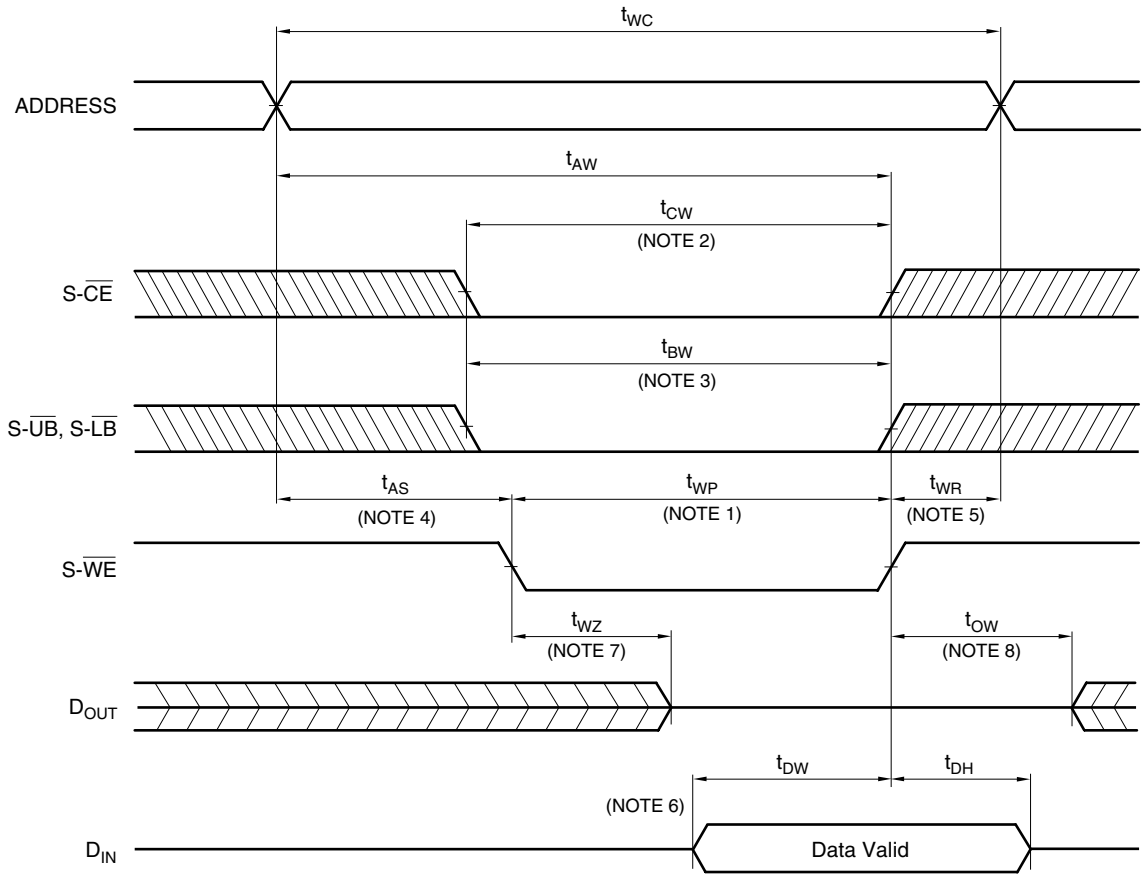


Figure 9. Read Cycle Timing Diagram

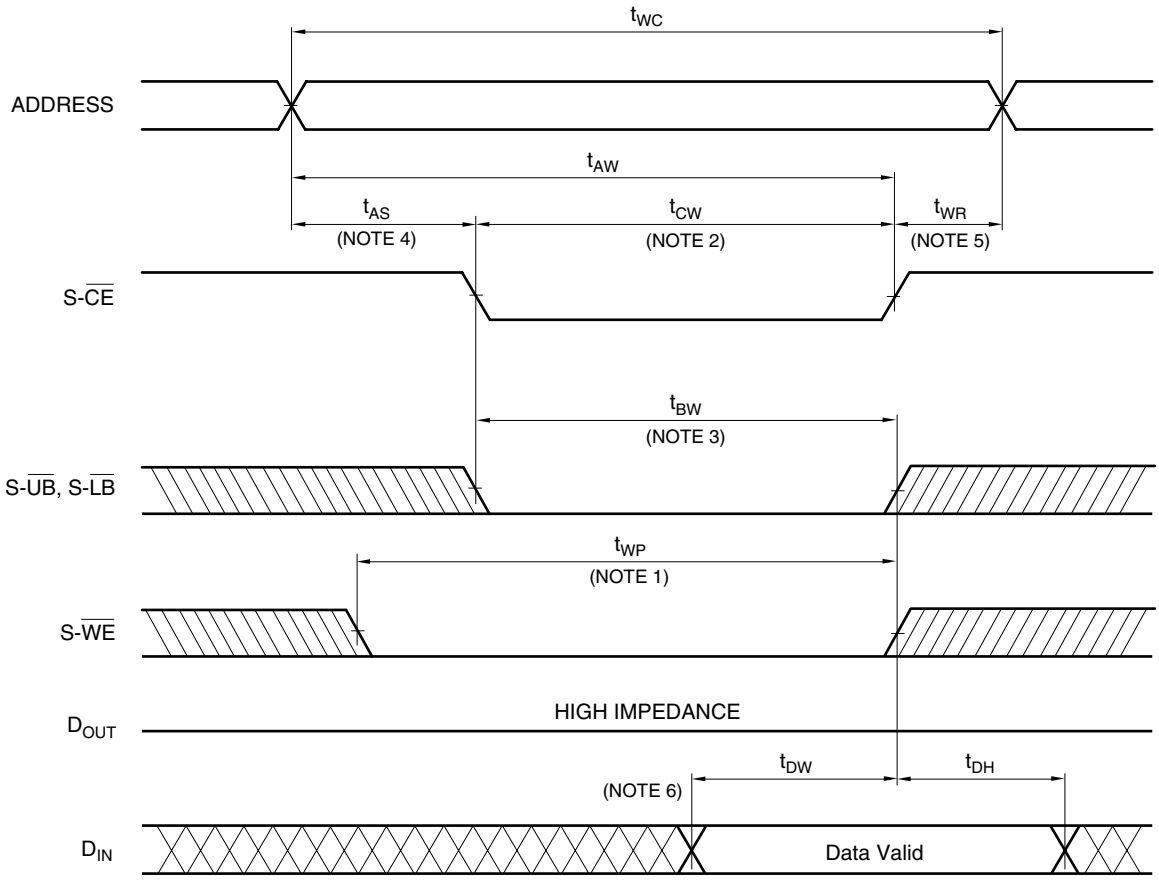


NOTES:

1. A write occurs during the overlap of a LOW S-$\overline{CE}$, LOW S-$\overline{WE}$ and LOW S-$\overline{UB}$ or LOW S-$\overline{LB}$.
2. t_{CW} is measured from the later of going LOW S-$\overline{CE}$ to the end of write.
3. t_{BW} is measured from the later of going LOW S-$\overline{UB}$ or LOW S-$\overline{LB}$ to the end of write.
4. t_{AS} is measured from the address valid to the beginning of write.
5. t_{WR} is measured from the end of write to the address change. t_{WR} applies in case a write ends at S-$\overline{CE}$ or S-$\overline{WE}$ going HIGH.
6. During this period, DQ pins are in the output state, therefore the input signals of opposite phase to the outputs must not be applied.
7. If S-$\overline{CE}$ goes LOW simultaneously with S-$\overline{WE}$ going LOW or after S-$\overline{WE}$ going LOW, the outputs remain in HIGH impedance state.
8. If S-$\overline{CE}$ goes HIGH simultaneously with S-$\overline{WE}$ going HIGH or before S-$\overline{WE}$ going HIGH, the outputs remain in HIGH impedance state.

1327-9

Figure 10. Write Cycle Timing Diagram (S-$\overline{WE}$ Controlled)

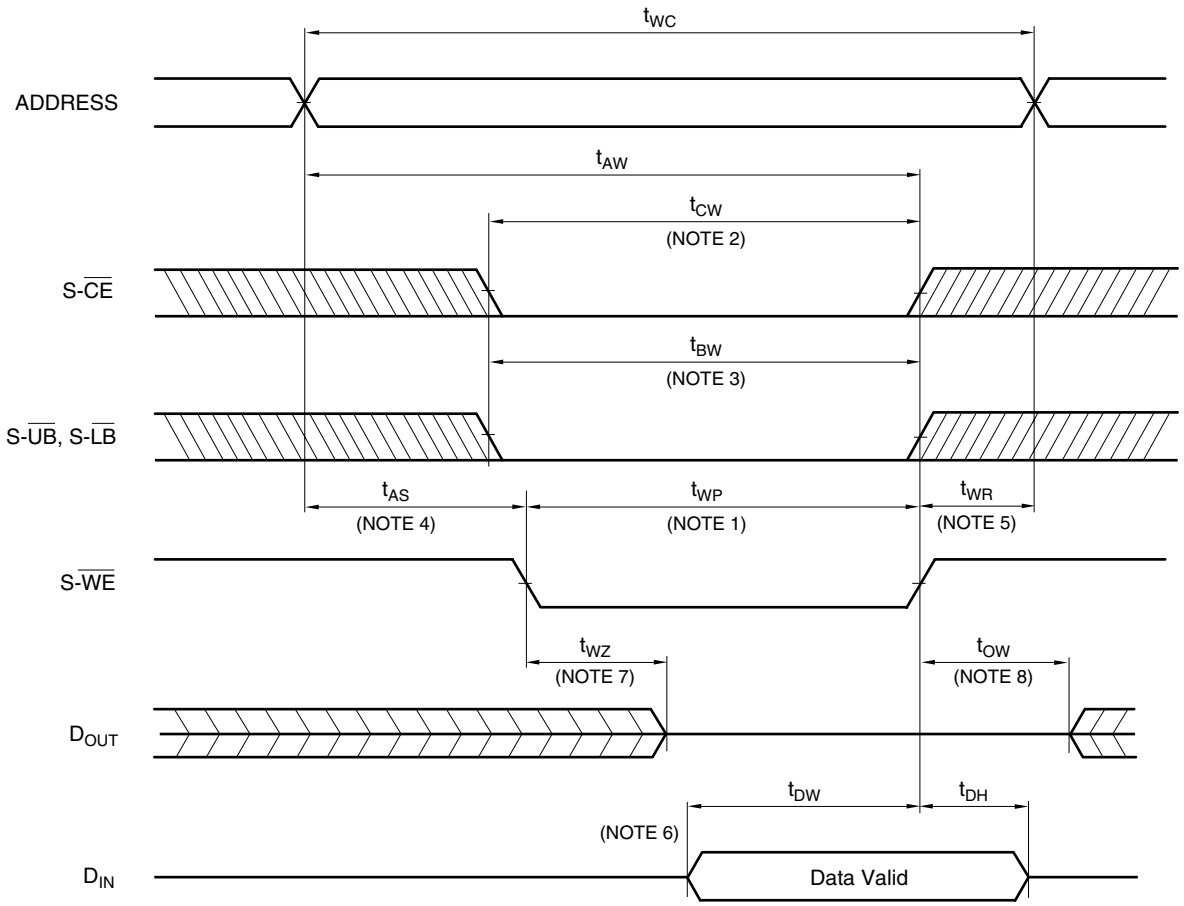


NOTES:

1. A write occurs during the overlap of a LOW S-$\overline{CE}$, LOW S-$\overline{WE}$ and LOW S-$\overline{UB}$ or LOW S-$\overline{LB}$.
2. t_{CW} is measured from the later of going LOW S-$\overline{CE}$ to the end of write.
3. t_{BW} is measured from the later of going LOW S-$\overline{UB}$ or LOW S-$\overline{LB}$ to the end of write.
4. t_{AS} is measured from the address valid to the beginning of write.
5. t_{WR} is measured from the end of write to the address change. t_{WR} applies in case a write ends at S-$\overline{CE}$ or S-$\overline{WE}$ going HIGH.
6. During this period, DQ pins are in the output state, therefore the input signals of opposite phase to the outputs must not be applied.
7. If S-$\overline{CE}$ goes LOW simultaneously with S-$\overline{WE}$ going LOW or after S-$\overline{WE}$ going LOW, the outputs remain in HIGH impedance state.
8. If S-$\overline{CE}$ goes HIGH simultaneously with S-$\overline{WE}$ going HIGH or before S-$\overline{WE}$ going HIGH, the outputs remain in HIGH impedance state.

1327-10

Figure 11. Write Cycle Timing Diagram (S-$\overline{CE}$ Controlled)



NOTES:

1. A write occurs during the overlap of a LOW S-$\overline{CE}$, LOW S-$\overline{WE}$ and LOW S-$\overline{UB}$ or LOW S-$\overline{LB}$.
2. t_{CW} is measured from the later of going LOW S-$\overline{CE}$ to the end of write.
3. t_{BW} is measured from the later of going LOW S-$\overline{UB}$ or LOW S-$\overline{LB}$ to the end of write.
4. t_{AS} is measured from the address valid to the beginning of write.
5. t_{WR} is measured from the end of write to the address change. t_{WR} applies in case a write ends at S-$\overline{CE}$ or S-$\overline{WE}$ going HIGH.
6. During this period, DQ pins are in the output state, therefore the input signals of opposite phase to the outputs must not be applied.
7. If S-$\overline{CE}$ goes LOW simultaneously with S-$\overline{WE}$ going LOW or after S-$\overline{WE}$ going LOW, the outputs remain in HIGH impedance state.
8. If S-$\overline{CE}$ goes HIGH simultaneously with S-$\overline{WE}$ going HIGH or before S-$\overline{WE}$ going HIGH, the outputs remain in HIGH impedance state.

1327-11

Figure 12. Write Cycle Timing (S-$\overline{UB}$, S-$\overline{LB}$ Controlled)

SRAM DATA RETENTION CHARACTERISTICS

T_A = -40°C to +85°C

PARAMETER	SYMBOL	CONDITIONS	MIN.	TYP.*	MAX.	UNIT
Data Retention Supply Voltage	V_{CCDR}	S-CE ≥ V_{CCDR} – 0.2 V	2.0		3.6	V
Data Retention Supply Current	I_{CCDR}	V_{CCDR} = 3 V, S-CE ≥ V_{CCDR} – 0.2 V			35	µA
Chip Enable Setup Time	t_{CDR}		0			ns
Chip Enable Hold Time	t_R		5			ms

NOTES: *Reference value at T_A = 25°C, S-V_{CC} = 3.0 V.

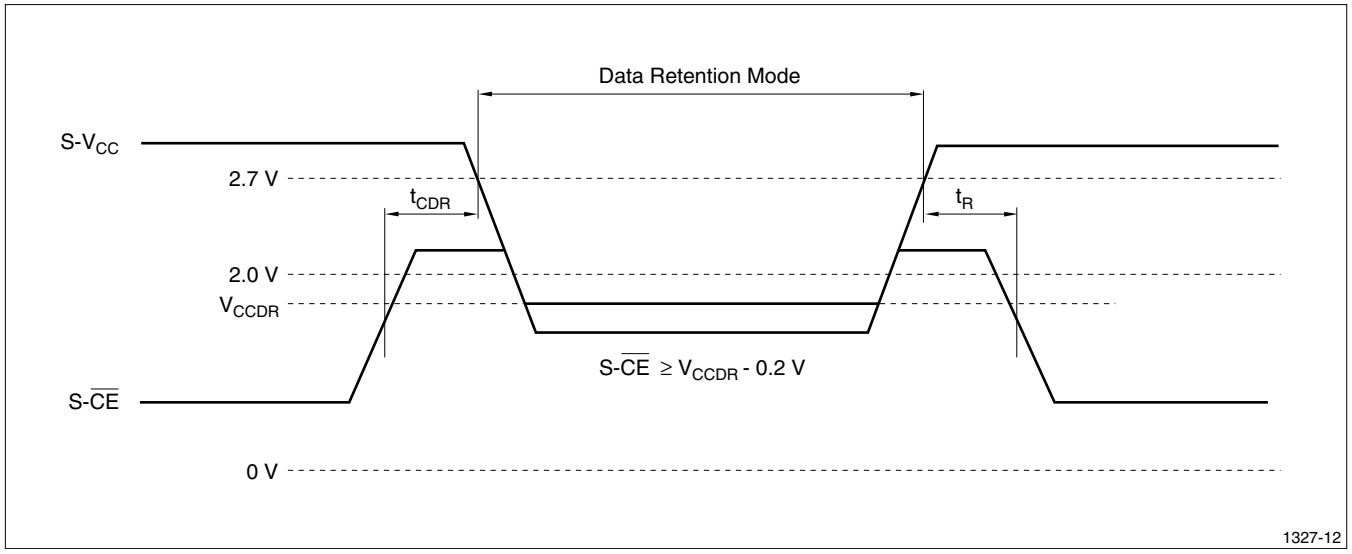


Figure 13. Data Retention Timing Diagram (S-$\overline{CE}$ Controlled)

GENERAL DESIGN GUIDELINES

Supply Power

Maximum difference (between F-V_{CC} and S-V_{CC}) of the voltage is less than 0.3 V.

Power Supply and Chip Enable of Flash Memory and SRAM

S-$\overline{CE}$ should not be LOW when F-$\overline{CE}$ is LOW simultaneously.

If the two memories are active together, they may not operate normally because of interference noises or data collision on DQ bus.

Both F-V_{CC} and S-V_{CC} need to be applied by the recommended supply voltage at the same time except SRAM data retention mode.

Power Up Sequence

When turning on Flash memory power supply, keep F-$\overline{RP}$ LOW. After F-V_{CC} reaches over 2.7 V, keep F-$\overline{RP}$ LOW for more than 100 ns.

Device Decoupling

The power supply needs to be designed carefully because one of the SRAM and the Flash Memory is in standby mode when the other is active. A careful decoupling of power supplies is necessary between SRAM and Flash Memory. Note peak current caused by transition of control signals (F-$\overline{CE}$, S-$\overline{CE}$).

FLASH MEMORY DATA PROTECTION

Noises having a level exceeding the limit specified in the specification may be generated under specific operating conditions on some systems.

Such noises, when induced onto F-$\overline{WE}$ signal or power supply may be interpreted as false commands, causing undesired memory updating.

To protect the data store in the flash memory against unwanted overwriting, systems operating with the flash memory should have the following write protect designs, as appropriate.

Protecting Data in Specific Block

By setting a F-$\overline{WP}$ to LOW, only the boot block can be protected against overwriting.

Parameter and main blocks cannot be locked.

System program, etc., can be locked by storing them in the book block.

When a high voltage is applied to F-$\overline{RP}$, overwrite opeartion is enabled for all blocks.

For further information on setting/resetting of block bit, and controlling of F-$\overline{WP}$ and F-$\overline{RP}$, refer to the specification, see the Command Definitions section.

Data Protection Through V_{PP}

When the level of V_{PP} is lower than V_{PPLK} (lockout voltage), write operation on the flash memory is disabled. All blocks are locked and the data in the blocks are completely write protected.

For the lockout voltage refer to the 'DC Characteristics' section.

Data Protection During Voltage Transition

DATA PROTECTION THROUGH F-$\overline{RP}$

When the F-$\overline{RP}$ is kept LOW during power up and power down sequence, write operation on the flash memory is disabled, write protecting all blocks

For details of F-$\overline{RP}$ control refer to the 'Flash Memory AC Electrical Characteristics' section.

DESIGN CONSIDERATIONS

Power Supply Decoupling

To avoid a bad effect on the system by flash memory power switching characteristics, each device should have a 0.1 µF ceramic capacitor connected between its V_{CC} and GND and between its V_{PP} and GND. LOW inductance capacitors should be placed as close as possible to package leads.

V_{PP} Trace on Printed Circuit Boards

Updating the memory contents of flash memories that reside in the target system requires that the printed circuit board designer pay attention to the V_{PP} Power Supply trace. Use similar trace widths and layout considerations given to the V_{CC} power bus.

The Inhibition of Overwrite Operation

Please do not execute reprogramming '0' for the bit which has already been programmed '0'. Overwrite operation may generate unerasable bit. In case of reprogramming '0' to the data which has been programmed '1'.

- Program '0' for the bit in which you want to change data from '1' to '0'.
- Program '1' for the bit which has already been programmed '0'.

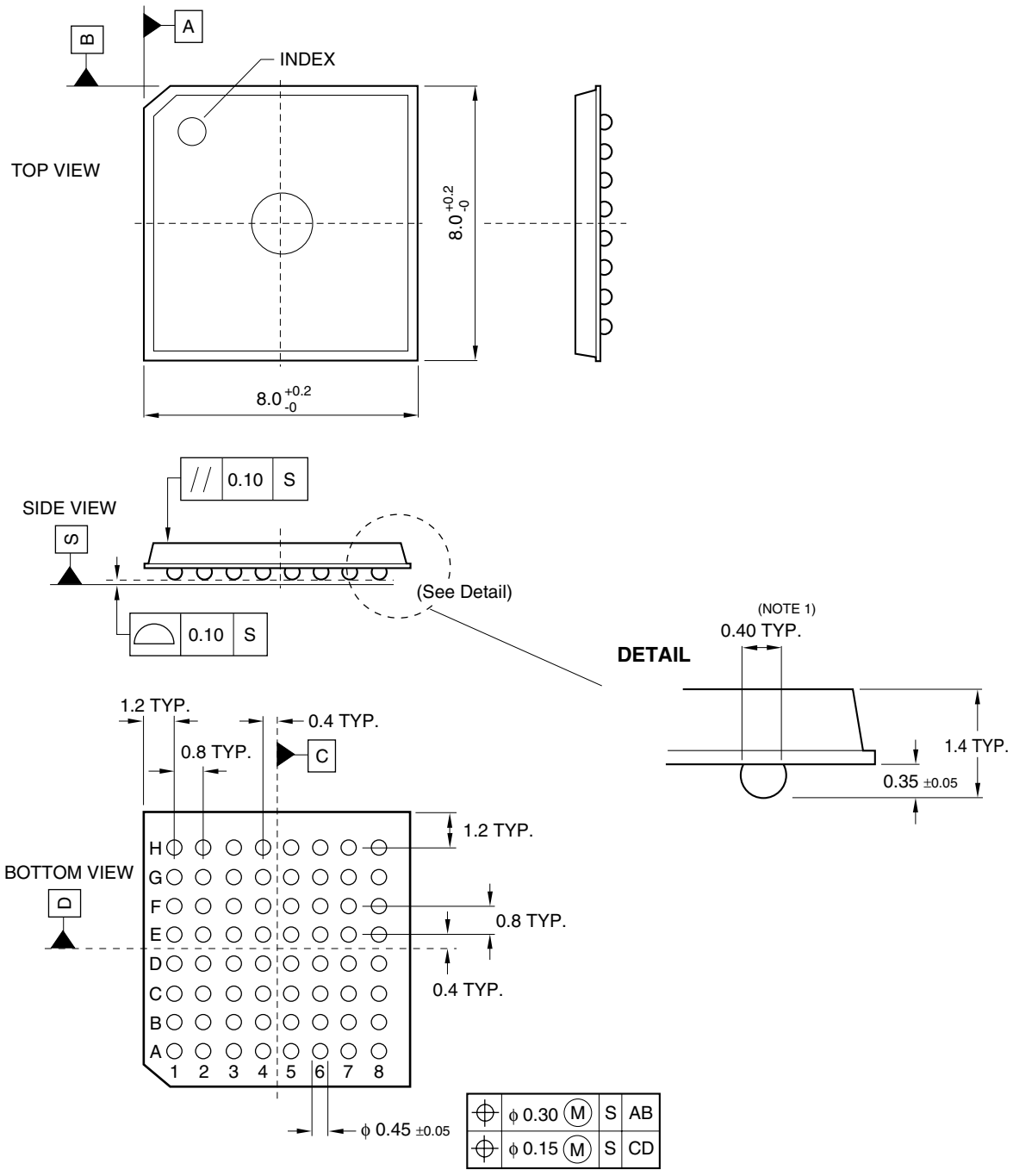
For example, changing data from '1011110110111101' to '1010110110111100' requires '1110111111111110' programming.

Power Supply

Block erase, full chip erase, word write and lock-bit configuration with an invalid V_{PP} (see 'DC Characteristics') produce spurious results and should not be attempted. Device operations at invalid V_{CC} voltage product spurious results and should note be attempted.

OUTLINE DIMENSIONS

FBGA064-P-0808



NOTES:
1. Land hole diameter for ball mounting.
2. Dimensions are in mm.

64FBGA

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SHARP components should not be used in medical devices with life support functions or in safety equipment (or similiar applications where component failure would result in loss of life or physical harm) without the written approval of an officer of the SHARP Corporation.

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